

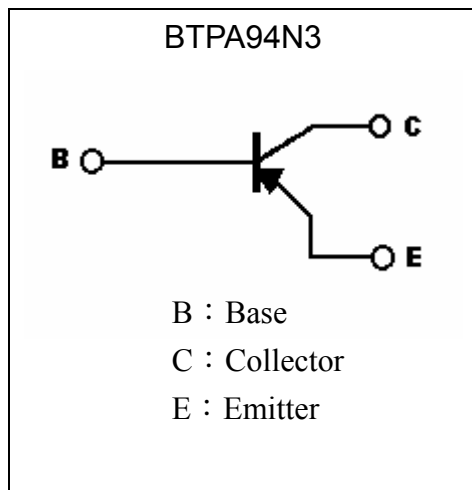
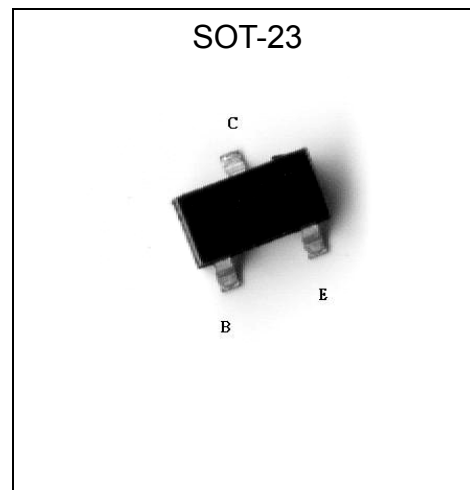
High Voltage PNP Epitaxial Planar Transistor

BV_{CEO}	-400V
I_C	-0.15A
$V_{CESAT(max)}$	-0.3V

BTPA94N3

Description

- High breakdown voltage. ($BV_{CEO}=-400V$)
- Low saturation voltage, typically $V_{CE(sat)} = -0.07V$ at $I_C/I_B = -10mA/-1mA$.
- Wide SOA (safe operation area).
- Complementary to BTNA44N3.
- Pb-free package

Symbol

Outline

Absolute Maximum Ratings ($T_a=25^{\circ}C$)

Parameter	Symbol	Limits	Unit
Collector-Base Voltage	V_{CBO}	-400	V
Collector-Emitter Voltage	V_{CEO}	-400	V
Emitter-Base Voltage	V_{EBO}	-6	V
Collector Current	I_C	-150	mA
Power Dissipation	P_d	350	mW
Thermal Resistance, Junction to Ambient	$R_{\theta JA}$	357	$^{\circ}C/W$
Junction Temperature	T_j	150	$^{\circ}C$
Storage Temperature	T_{stg}	-55~+150	$^{\circ}C$

**Characteristics (Ta=25°C)**

Symbol	Min.	Typ.	Max.	Unit	Test Conditions
BVCBO	-400	-	-	V	IC=-50μA
BVCEO	-400	-	-	V	IC=-1mA
BVEBO	-6	-	-	V	IE=-50μA
ICBO	-	-	-100	nA	VCB=-400V
IEBO	-	-	-100	nA	VEB=-6V
ICES	-	-	-500	nA	VCE=-400V
VCE(sat) 1	-	-	-0.2	V	IC=-1mA, IB=-0.1mA
*VCE(sat) 2	-	-	-0.2	V	IC=-10mA, IB=-1mA
*VCE(sat) 3	-	-	-0.3	V	IC=-50mA, IB=-5mA
*VBE(sat)	-	-	-0.9	V	IC=-20mA, IB=-2mA
hFE 1	80	-	-	-	VCE=-10V, IC=-1mA
*hFE 2	100	-	270	-	VCE=-10V, IC=-10mA
*hFE 3	50	-	-	-	VCE=-10V, IC=-50mA
*hFE 4	20	-	-	-	VCE=-10V, IC=-100mA
Cob	-	-	6	pF	VCB=-10V, IE=0A, f=1MHz

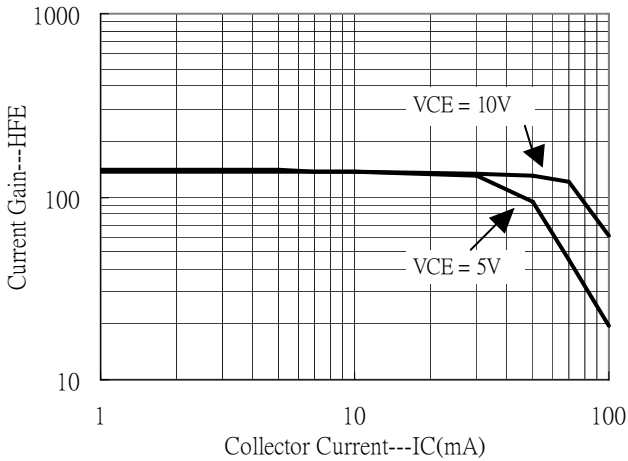
*Pulse Test: Pulse Width ≤380μs, Duty Cycle≤2%

Ordering Information

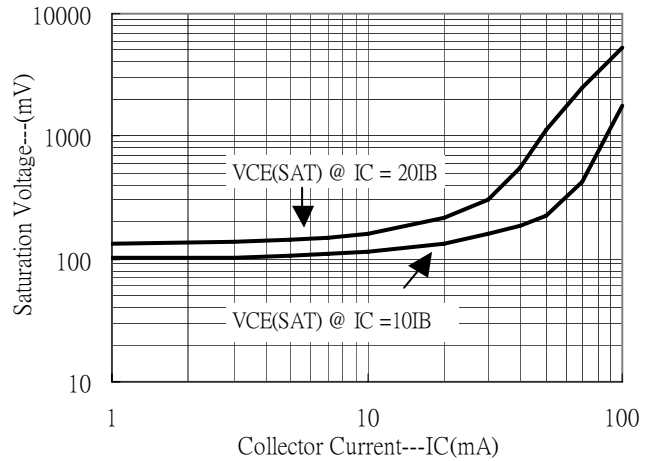
Device	Package	Shipping	Marking
BTPA94N3	SOT-23 (Pb-free)	3000 pcs / Tape & Reel	4Z

Characteristic Curves

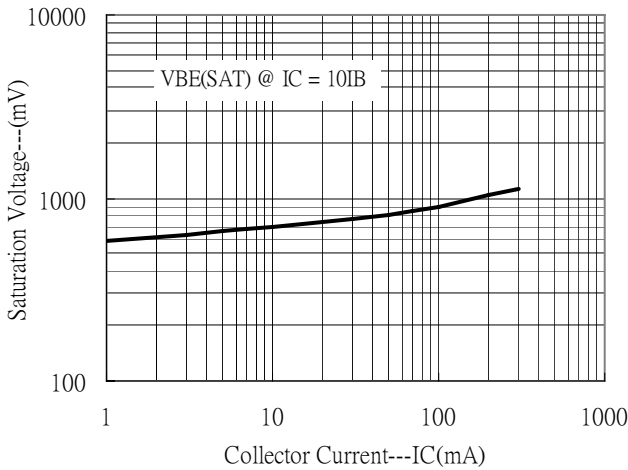
Current Gian vs Collector Current



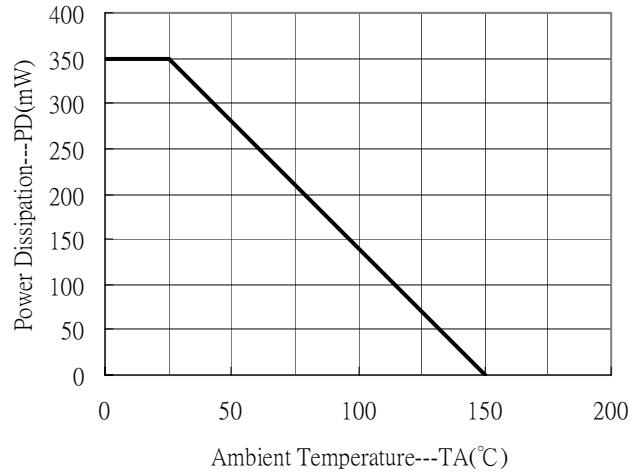
Saturation Voltage vs Collector Current



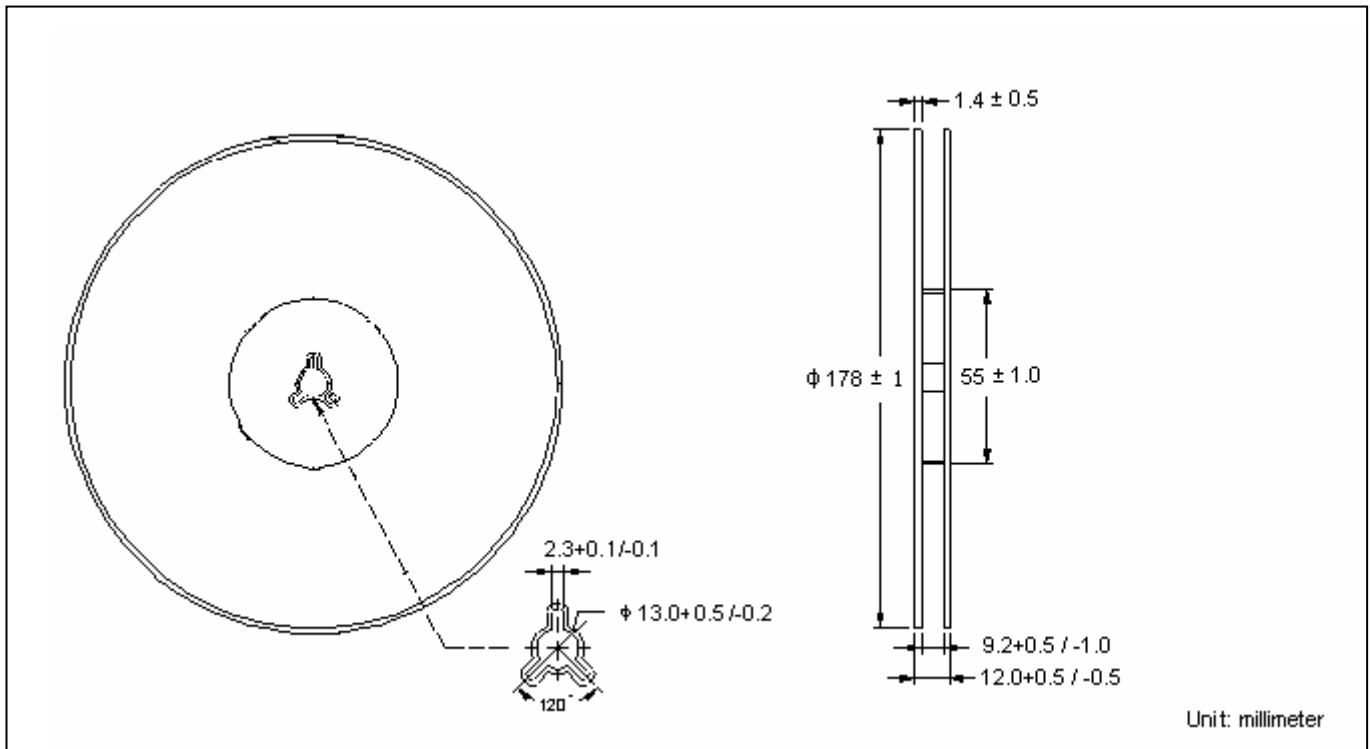
Saturation Voltage vs Collector Current



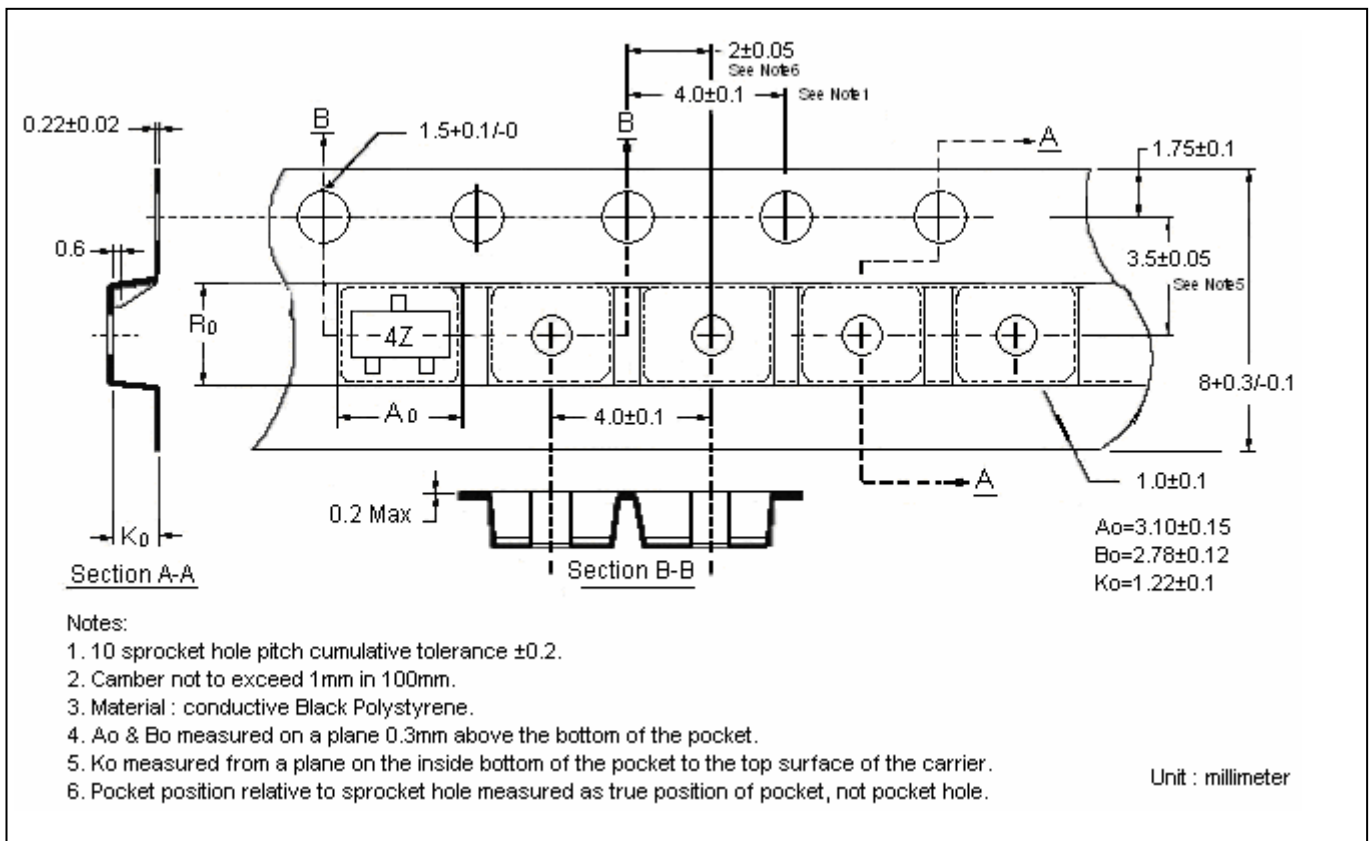
Power Derating Curve



Reel Dimension



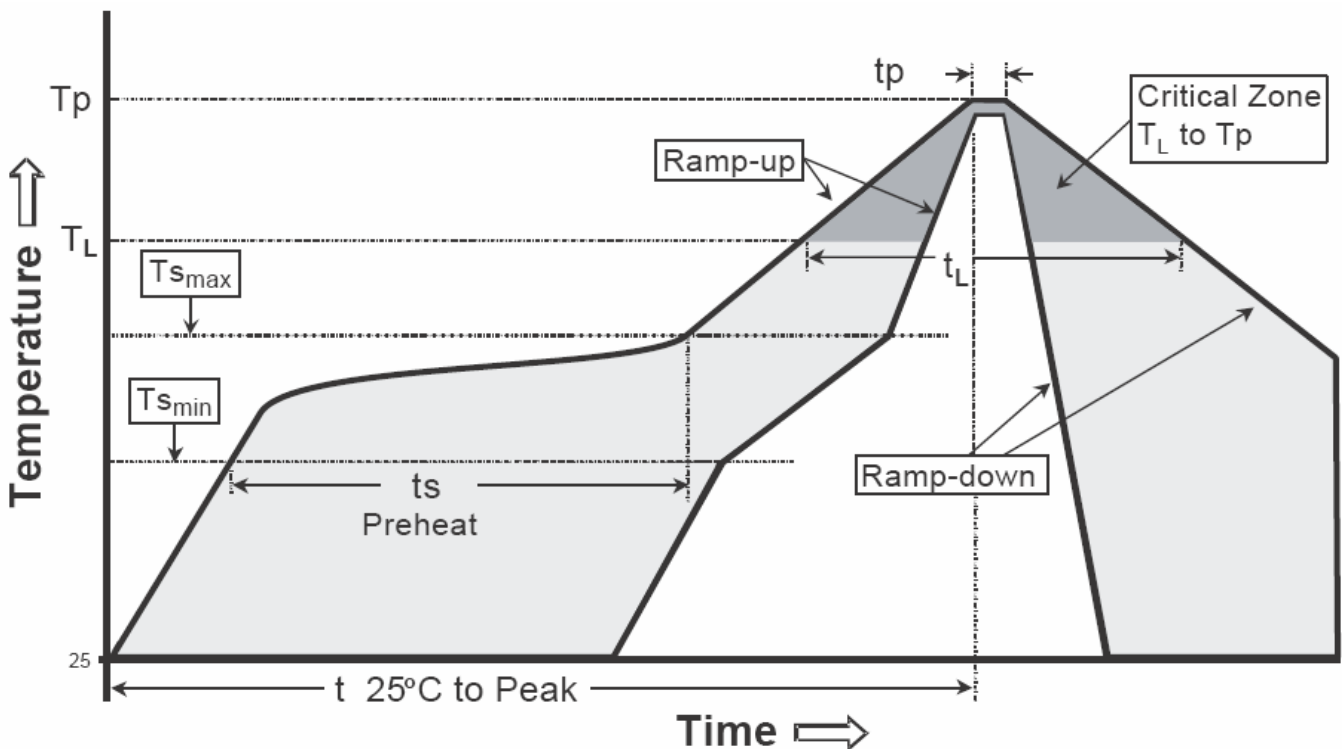
Carrier Tape Dimension



Recommended wave soldering condition

Product	Peak Temperature	Soldering Time
Pb-free devices	260 +0/-5 °C	5 +1/-1 seconds

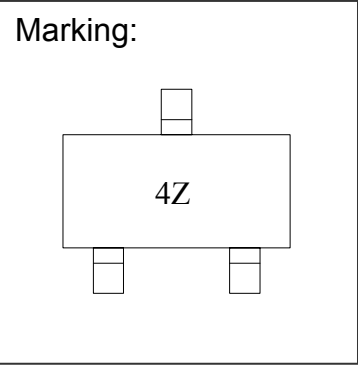
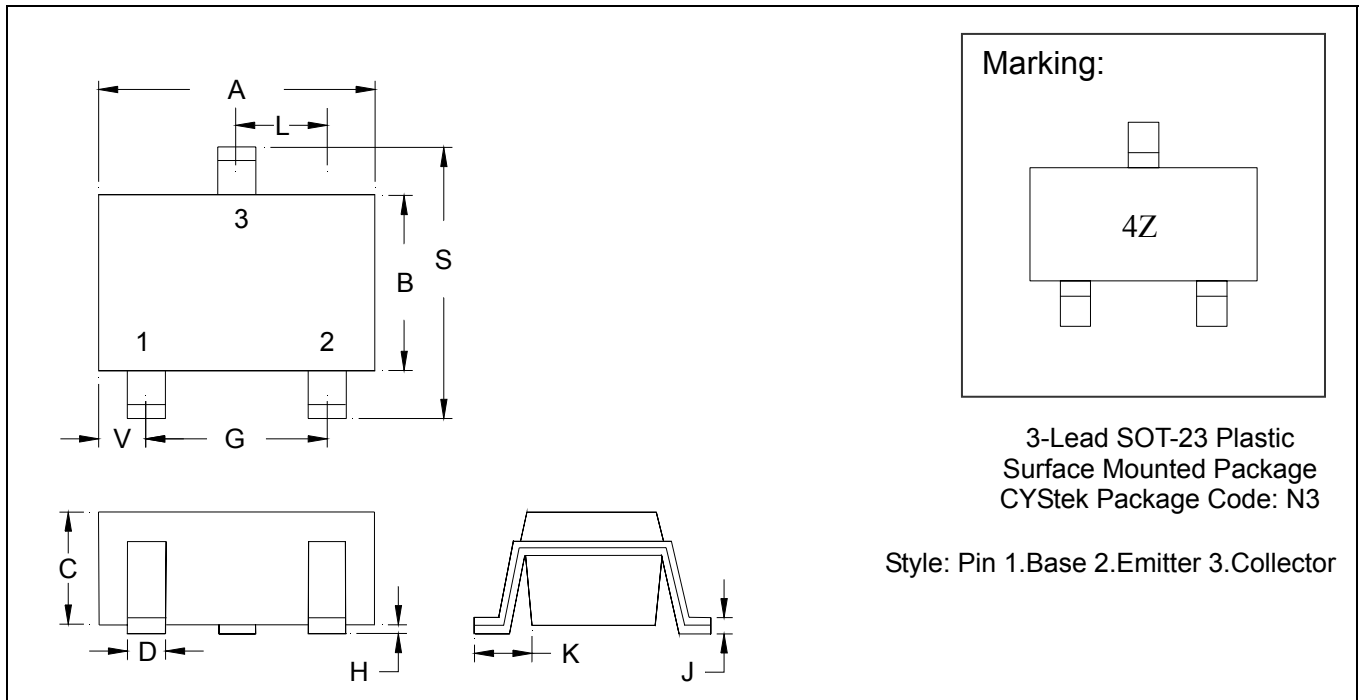
Recommended temperature profile for IR reflow



Profile feature	Sn-Pb eutectic Assembly	Pb-free Assembly
Average ramp-up rate (Tsmax to Tp)	3°C/second max.	3°C/second max.
Preheat		
-Temperature Min(Ts min)	100°C	150°C
-Temperature Max(Ts max)	150°C	200°C
-Time(ts min to ts max)	60-120 seconds	60-180 seconds
Time maintained above:		
-Temperature (TL)	183°C	217°C
- Time (tL)	60-150 seconds	60-150 seconds
Peak Temperature(TP)	240 +0/-5 °C	260 +0/-5 °C
Time within 5°C of actual peak temperature(tp)	10-30 seconds	20-40 seconds
Ramp down rate	6°C/second max.	6°C/second max.
Time 25 °C to peak temperature	6 minutes max.	8 minutes max.

Note : All temperatures refer to topside of the package, measured on the package body surface.

SOT-23 Dimension



3-Lead SOT-23 Plastic
 Surface Mounted Package
 CYStek Package Code: N3

Style: Pin 1.Base 2.Emitter 3.Collector

*: Typical

DIM	Inches		Millimeters		DIM	Inches		Millimeters	
	Min.	Max.	Min.	Max.		Min.	Max.	Min.	Max.
A	0.1102	0.1204	2.80	3.04	J	0.0034	0.0070	0.085	0.177
B	0.0472	0.0630	1.20	1.60	K	0.0128	0.0266	0.32	0.67
C	0.0335	0.0512	0.89	1.30	L	0.0335	0.0453	0.85	1.15
D	0.0118	0.0197	0.30	0.50	S	0.0830	0.1083	2.10	2.75
G	0.0669	0.0910	1.70	2.30	V	0.0098	0.0256	0.25	0.65
H	0.0005	0.0040	0.013	0.10					

Notes: 1.Controlling dimension: millimeters.
 2.Maximum lead thickness includes lead finish thickness, and minimum lead thickness is the minimum thickness of base material.
 3.If there is any question with packing specification or packing method, please contact your local CYStek sales office.

Material:

- Lead: Pure tin plated.
- Mold Compound: Epoxy resin family, flammability solid burning class: UL94V-0.

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